

**Notice of References Cited**

Application/Control No.

09/808,067

Applicant(s)/Patent Under

Reexamination

ABBOTT ET AL.

Examiner

Scott L. Jarrett

Art Unit

3623

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	X	Jayaraman V. et al., A closed-loop logistics model for remanufacturing Journal of the Operational Research Society, Vol. 50, 1999, Pages 497-508

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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